

<b>Notice of References Cited</b>	Application/Control No. 09/922,065	Applicant(s)/Patent Under Reexamination MAR ET AL.	
	Examiner Ted M Wang	Art Unit 2634	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,337,014	08-1994	Najle et al.	324/613
	B	US-6,313,619	11-2001	Roth, Alexander	324/76.19
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Application Note 1EPAN 16E, Phase Noise measurements with Spectrum Analyzers of the FSE family, 02 Oct. 95, Josef Wolf
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.